## TOSHIBA

Unit: mm

TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (Ultra High speed U-MOSIII)

PRELIMINARY

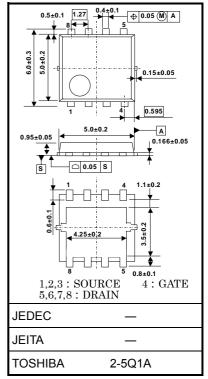
**TPCA8011-H** 

High Speed and High Efficiency DC-DC Converters Notebook PC Applications Portable Equipment Applications

- Small footprint due to small and thin package
- High speed switching
- Small gate charge: Qsw = 11 nC (typ.)
- Low drain-source ON resistance:  $R_{DS}$  (ON) = 3.1 m $\Omega$  (typ.)
- High forward transfer admittance:  $|\,Y_{\rm fs}|$  = TBD S (typ.)
- Low leakage current:  $I_{DSS} = 10 \ \mu A \ (max) \ (V_{DS} = 30 \ V)$
- Enhancement mode:  $V_{th}$  = 1.1 to 2.3 V (V\_{DS} = 10 V,  $I_{D}$  = 1 mA)

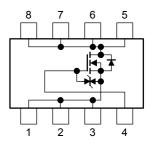
#### Maximum Ratings (Ta = 25°C)

Characte	ristics	Symbol	Rating	Unit	
Drain-source voltage		V <sub>DSS</sub>	20	V	
Drain-gate voltage (R	$R_{\rm GS} = 20 \ \rm k\Omega$ )	V <sub>DGR</sub>	20	V	
Gate-source voltage		V <sub>GSS</sub>	±12	V	
Drain current	DC (Note 1)	I <sub>D</sub>	40	А	
Diameditent	Pulsed (Note 1)	I <sub>DP</sub>	120	~	
Drain power dissipati	on (Tc=25 )	PD	45	W	
Drain power dissipati	on (t = 10 s) (Note 2a)	PD	2.8	W	
Drain power dissipati	on (t = 10 s) (Note 2b)	PD	1.6	W	
Single pulse avalancl	ne energy (Note 3)	E <sub>AS</sub>	208	mJ	
Avalanche current		I <sub>AR</sub>	40	А	
Repetitive avalanche (1	energy c=25) (Note 4)	E <sub>AR</sub>	TBD	mJ	
Channel temperature	nnel temperature T <sub>ch</sub> 150				
Storage temperature	range	T <sub>stg</sub>	-55 to 150	°C	



Weight: 0.080 g (typ.)

#### **Circuit Configuration**



Note: For (Note 1), (Note 2), (Note 3), (Note 4), please refer to the next page.

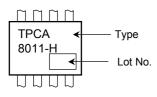
This transistor is an electrostatic sensitive device. Please handle with caution.

# TOSHIBA

## **Thermal Characteristics**

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case (Tc=25)	R <sub>th (ch-c)</sub>	2.78	°C/W
Thermal resistance, channel to ambient (t = 10 s) (Note 2a)	R <sub>th (ch-a)</sub>	44.6	°C/W
Thermal resistance, channel to ambient (t = 10 s) (Note 2b)	R <sub>th (ch-a)</sub>	78.1	°C/W

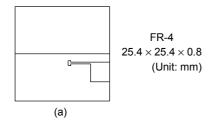
### Marking (Note 5)

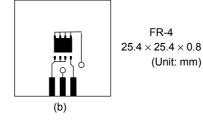


Note 1: Please use devices on condition that the channel temperature is below 150°C.

Note 2: (a) Device mounted on a glass-epoxy board (a)

(b) Device mounted on a glass-epoxy board (b)





Note 3:  $V_{DD} = 24 \text{ V}, \text{ T}_{ch} = 25^{\circ}\text{C}$  (initial), L = 0.1 mH, R<sub>G</sub> = 25  $\Omega$ , I<sub>AR</sub> = 35 A

Note 4: Repetitive rating: pulse width limited by max channel temperature

Note 5: \* Weekly code: (Three digits)



Week of manufacture

\_(01 for first week of year, continues up to 52 or 53)

Year of manufacture (One low-order digits of calendar year)

Electrical Characteristics (Ta = 25°C)

Ch	aracteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cur	rrent	I <sub>GSS</sub>	$V_{GS}=\pm 10V,V_{DS}=0~V$	_		±10	μΑ
Drain cut-OFF cu	ırrent	I <sub>DSS</sub>	$V_{DS} = 20 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$		_	10	μA
Drain-source bre	•	V (BR) DSS	$I_{D} = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	20	—		v
		V (BR) DSX	$I_D = 10 \text{ mA}, V_{GS} = -12 \text{ V}$	8	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	v	
Gate threshold v	oltage	V <sub>th</sub>	$V_{DS} = 10 \text{ V}, \text{ I}_{D} = 200  \mu \text{ A}$	0.5	—	1.2	V
	ragistance	Proven	$V_{GS} = 2.5 \text{ V}, \text{ I}_{D} = 20 \text{ A}$	_	4.0	5.4	-mΩ
Dialit-Source ON	Tesistance	R <sub>DS (ON)</sub>	$V_{GS}=4.5V,\ I_D=20\ A$	_	3.1	4.1	
Forward transfer	admittance	Y <sub>fs</sub>	$V_{DS} = 10 \text{ V}, \text{ I}_{D} = 20 \text{ A}$	TBD	TBD	_	S
Input capacitance		C <sub>iss</sub>		_	1870	_	~F
Reverse transfer capacitance		C <sub>rss</sub>	$V_{DS} = 10 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ f} = 1 \text{ MHz}$	_	312	_	pF
Output capacitance		C <sub>oss</sub>		_	1370	_	
Switching time	Rise time	t <sub>r</sub>	$V_{GS} \stackrel{5}{\overset{0}{}_{O}} \bigvee \prod_{O} \stackrel{I_{D}}{\overset{O}{\underset{O}}} \stackrel{I_{D}}{\overset{O}{\underset{O}}} \stackrel{O}{\overset{O}{\underset{O}}} \bigvee \stackrel{O}{\overset{O}{\underset{O}}} \stackrel{O}{\overset{O}}} \stackrel{O}{\overset{O}} \stackrel{O}{\overset{O}{\underset{O}}} \stackrel{O}{\overset{O}}} \stackrel{O}{\overset{O}} \stackrel{O}{\overset{O}}} \stackrel{O}{\overset{O}} \stackrel{O}{\overset{O}}} \stackrel{O}{\overset{O}} \stackrel{O}{\overset{O}}} \stackrel{O}{\overset{O}} \stackrel{O}}{\overset{O}} \stackrel{O}{\overset{O}} \overset{O} \overset{O}} \overset{O} \overset{O}} \overset{O} \overset{O}}{\overset{O}} \overset{O} \overset{O}} \overset{O}} \overset{O} \overset{O}} \overset{O}} \overset{O} \overset{O} \overset{O}} \overset{O} \overset{O}} $		TBD	_	- ns
	Turn-ON time	t <sub>on</sub>			TBD	_	
	Fall time	t <sub>f</sub>			TBD	_	
	Turn-OFF time	t <sub>off</sub>	$V_{DD}\simeq 10~V \label{eq:VDD}$ Duty $\leq$ 1%, $t_{W}$ = 10 $\mu s$		TBD	_	
Total gate charge	tal gate charge		$V_{DD}\simeq 16~V,~V_{GS}=10~V,~I_{D}=40~A$		38	_	
(gate-source plus	s gate-drain)	Qg	$V_{DD}\simeq 16~V,~V_{GS}=5~V,~I_{D}=40~A$		TBD	_	
Gate-source charge 1		Q <sub>gs1</sub>			TBD	_	nC
Gate-drain ("miller") charge		Q <sub>gd</sub>	$V_{DD} \simeq 16 \text{ V}, \text{ V}_{GS} = 10 \text{ V}, \text{ I}_{D} = 40 \text{ A}$	_	8	_	
Gate switch char	ge	Q <sub>SW</sub>		_	11	_	

### Source-Drain Ratings and Characteristics (Ta = 25°C)

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit	
Drain reverse current	Pulse	(Note 1)	I <sub>DRP</sub>	_	_	_	120	А
Forward voltage (diode)			V <sub>DSF</sub>	$I_{DR} = 40 \text{ A}, V_{GS} = 0 \text{ V}$	_	_	-1.2	V

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